

LOGIC ELEMENT CONNECTION INFORMATION COMPILING METHOD

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 Applicant: RENESAS TECHNOLOGY CORP.; RENESAS LSI DESIGN CORP.

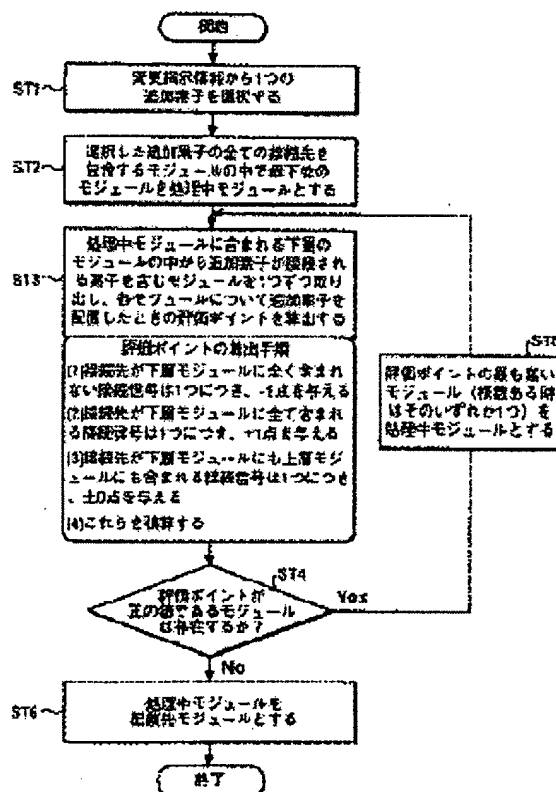
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 - european:
 Application number: JP20020171630 20020612
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Abstract of JP2004021315

PROBLEM TO BE SOLVED: To acquire logic element connection information in which the number of pins to be newly generated in a connection destination module is small, and alternate wiring is small.

SOLUTION: The least significant module among modules including all additional elements selected from change instruction information is defined as a module under processing, and modules including elements to which the additional elements are connected are extracted one by one from underlayer modules included in the module under processing, and evaluation points at the time of arranging the additional elements are calculated (steps ST1 to ST3). When modules whose evaluation points have positive values are present (step ST4: Yes), the module whose evaluation point is the highest (any one module when there are a plurality of such modules) is defined as the module under processing (steps ST5 to ST3). When only modules whose evaluation points are not more than 0 are found (a step ST4: No), the module under processing at that time is defined as an arrangement destination module (a step ST6).



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(43) Date of application
publication: **22.01.04**(84) Designated contracting
states:(71) Applicant: **RENESAS TECHNOLOGY CORP**
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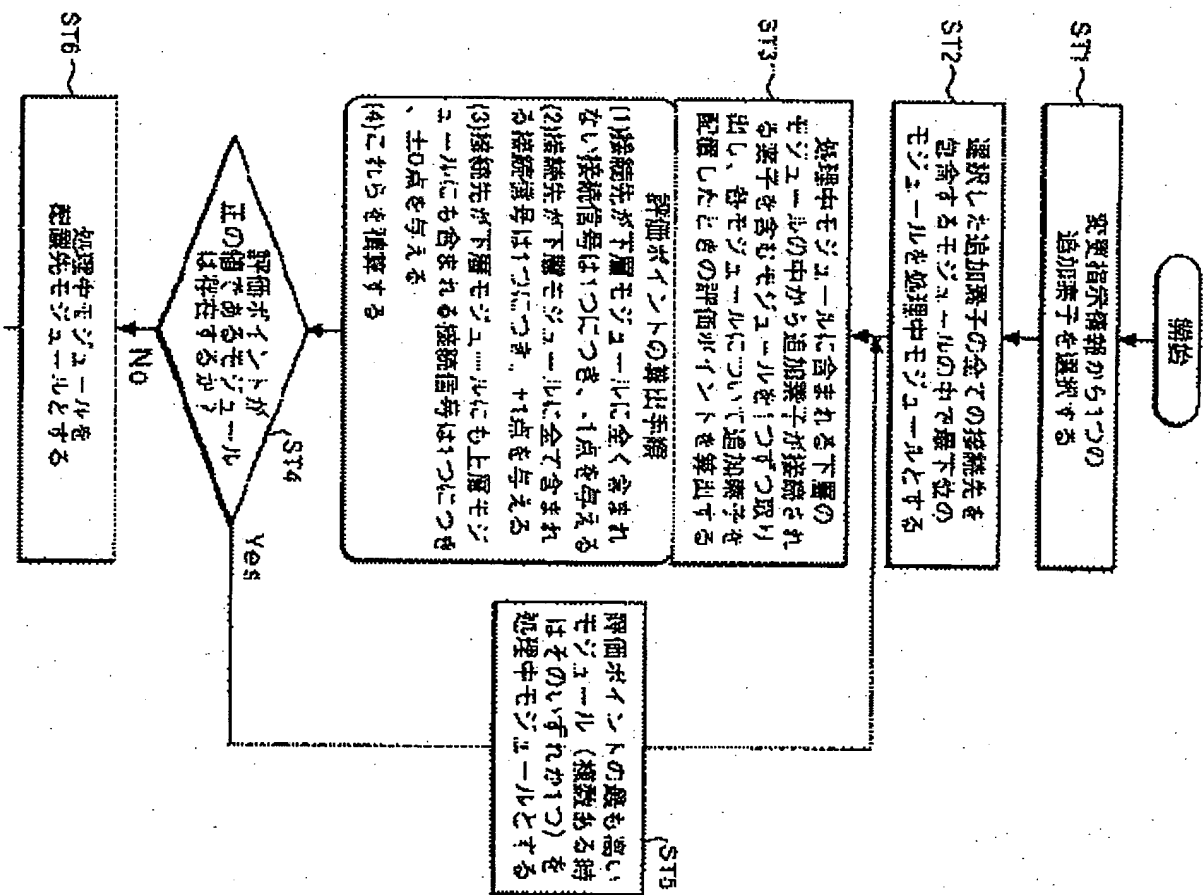
**(54) LOGIC ELEMENT
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(57) Abstract:

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JP04021315A2: OVERVOLTAGE PREVENTING CIRCUIT

Derwent Title: Overvoltage protection circuit for telephone subscriber line - has current interruption switch circuits connected respectively and turned off with overvoltage detection NoAbstract Dwg 1/4 [Derwent Record](#)

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Kind: A

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Published / Filed: 1992-01-24 / 1990-05-14

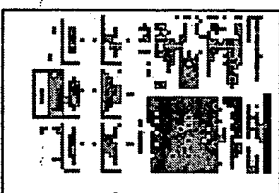
Application Number: JP1990000124403

IPC Code: H02H 3/20; H04M 3/18; H04M 3/22; H04Q 3/42;

Priority Number: 1990-05- JP1990000124403

Abstract:

PURPOSE: To obtain an overvoltage preventing circuit which automatically recovers when a malfunction is eliminated due to an insulating state obtained for the purpose of a circuit protection by providing a current breaker so balance-connected as to short-circuit to a voltage of a normal state and to be cut OFF when an overcurrent is applied, and a detector for latching the detected output of an overvoltage source cross-contact to output it.

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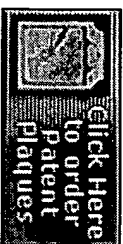
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CONSTITUTION: If subscribers' lines 14a, 14b have overvoltage source cross-contacts an overcurrent flows in a circuit of a subscriber's line 14a → a current breaker 11-1 → a receiver side → a current breaker 11-2 → subscriber's line 14b, and a detector 12 applies an overvoltage detection signal to the current breaker to stop supplying of a current. Thus, the breakers 11-1, 11-2 become insulating states of no current. The detector 12 monitors the currents or voltages of the lines 14a, 14b during an overvoltage cross-contact, and if the cross-contact is eliminated, the breakers 11-1, 11-2 are recovered to a conducting state. If the insulation of the lines are stopped during the cross-contact, a selector 13 is operated by an external control input. The circuit can be protected by the above operation.

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Family: None

Other Abstract Info: None



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